

**Search Notes**

Application/Control No.

09/780,308

Examiner

Djenane M. Bayard

Applicant(s)/Patent under  
Reexamination

SHIH ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
709	225	10/4/2005	DB
719	249	10/4/2005	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	10/5/2005	DB